



Deep Learning from Multi-Sourced Data

Guest Editors:

Dr. Gaoang Wang

International Campus, Zhejiang
University, Haining, China

Prof. Dr. Jenq-Neng Hwang

Department of Electrical and
Computer Engineering, University
of Washington, Seattle, WA, USA

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Message from the Guest Editors

Dear Colleagues,

With the fast development of deep learning technologies, vast quantities of data are usually required for deep model training. It is worth employing complementary and rich information from multiple sourced datasets when a single dataset can not meet the demand. However, several challenges remain in the learning of multi-sourced data. Firstly, multi-sourced data can have different modalities. Combining information from multi-modality data is usually difficult. Secondly, label inconsistency is another major issue. Some data samples are annotated with fine labels, while some have weak labels or in some cases no labels. Thirdly, there are annotation biases among different annotators, resulting in noisy label problems. Fourthly, domain gaps usually exist in multi-sourced data. Despite these challenges, there is a high demand for practical applications related to multi-sourced data. As a result, learning from multi-sourced data is garnering more and more attention.

In this Special Issue, we welcome original research, applications, and review articles in all areas related to learning from multi-sourced data.





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Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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